**VLSI Testing final project progress report**

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**Topic**

N-detect TDF Test Pattern Generator

**Current progress**

We divide this project into three parts :

1. TDF ATPG

* PA3 rewriting : Modify *podem.cpp* . Use SAF pattern generator without random fill and then shift the generated pattern to implement LOS. Finally, assign unknown PIs to meet TDF. (15% done. Random fill has removed, LOS on going)
* SCOAP : We want to apply SCOAP in ATPG. Currently code in PA3 has no considering of controllability.

1. N-detect

* [Benware 03] survey
* Implement

1. Compression

* [Hamzaoglu 98] [Xiang 14] survey
* DTC Implement
* STC Implement
* Optimization

**Schedule**

5/19 : TDF ATPG done/ N-detect on going / STC,DTC on going

5/23 : N-detect done/ STC done

5/26 : DTC done / Compression optimization on going

6/1 : Stop compression optimization /Run time optimization on going

6/6 : Stop Optimization/ analysis & PPT writing

6/9 : Presentation

6/16 : Final exam

6/17 : report writing/ DEMO preparing.